Industrial Computing Platform Partner

COM-LN

NPDP P2

Temp./Humidity Test Report

Report NO: 10E020003

Issued by:	Rex Chang	/	*01/21/2010*
	Test Engineer		**Date**
Reviewed by:	Wenyuan Yang	/	*01/21/2010*
	Manager		**Date**

Temperature / Humidity Test Report

1. **Test Date:** 01-15~21-2010

2. **Test Product:** COM-LN A0.2

3. **Test Site:** AAEON QA Internal Lab.

4. **Test Cause:** NPDP P2 stage

5. **Test Item:**
    1. 0~60dC Power On/Off
    2. 0~60dC Temperature Variation Test
    3. –5dC Cold Start & 65dC Hot Start Test

6. **Sample Configuration & Quantity Under Test:**
    1. CPU: Intel Atom D510 / 1.66GHz (BIOS Ver: 0.7)
    2. Memory: DSL 1GB * 2
       / ELPIDA E1116AESE (DDR2-667)
    3. CFD: PQI 32MB
    4. 2.5” SATA HDD: Fujitsu MHW2060BH / 60GB
    5. ATX Power Supply: Seventeam ST-350EAG-05G
    6. Carrier Board: ECB-916M A2.0
7. **Test Result:**
    1. No problem was found during the temp./humidity power on/off test.
    2. No problem was found during the temperature variation test.
    3. No problem was found during the cold Start and hot start test.